



4/17/2012

**RELIABILITY MONITOR REPORT  
FOR**

**X3 0.6 $\mu$ m Silicon Gate CMOS (C6)**

**MAXIM Integrated Products**

**120 San Gabriel Dr.  
Sunnyvale, CA 94086**

**This Report was prepared by  
Maxim Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX5048BAUT	MAX7325AEG+
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The calculated failure rate for devices using this process is:

**FAILURE RATE: MTTF (YRS): 8720 QUANTITY: 45 FAILS: 0 FITS: 13.1**

The parameters used to calculate this failure rate are as follows:

**Cf: 60% Ea: 0.7 Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2011 and 3/31/2012 .

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**Process Information:**

Process Description: X3 0.6µm Silicon Gate CMOS (C6)

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**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1044	MAX5048BAUT+	135C	1000 HRS	45	0	SH71HA050Q3
<b>Total:</b>						<b>0</b>	

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**STORAGE LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1141	MAX7325AEG+	150C	500 HRS	45	0	SYDABA049CB
<b>Total:</b>						<b>0</b>	

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**TEMPERATURE CYCLE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1141	MAX7325AEG+	-65C TO 150C	500 CYS	77	0	SYDABA049CB
<b>Total:</b>						<b>0</b>	

**FAILURE RATE: MTTF (YRS): 8720 QUANTITY: 45 FAILS: 0 FITS: 13.1**